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1 Time-redundant multiple computation for fault-tolerant digital neural networks

Yang-Ming Hsu; Piuri, V.; Swartzlander, E.E., Jr.;

 Circuits and Systems, 1995. ISCAS '95., 1995 IEEE International Symposium on , Volume: 2 , 28 April-3 May 1995
 Pages:977 - 980 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(380 KB\)\]](#) **IEEE CNF**
2 SEU fault tolerance in artificial neural networks

Velazco, R.; Assoum, A.; Radi, N.E.; Ecoffet, R.; Botey, X.;

 Nuclear Science, IEEE Transactions on , Volume: 42 , Issue: 6 , Dec. 1995
 Pages:1856 - 1862

[\[Abstract\]](#) [\[PDF Full-Text \(724 KB\)\]](#) **IEEE JNL**
3 Evidences of SEU tolerance for digital implementations of artificial neural networks: one year MPTB flight results

Velazco, R.; Cheynet, P.; Tissot, A.; Haussy, J.; Lambert, J.; Ecoffet, R.;

 Radiation and Its Effects on Components and Systems, 1999. RADECS 99. 19th Fifth European Conference on , 13-17 Sept. 1999
 Pages:565 - 568

[\[Abstract\]](#) [\[PDF Full-Text \(396 KB\)\]](#) **IEEE CNF**
4 Comments on "Linear circuit fault diagnosis using neuromorphic analyzers"

Fedi, G.; Manetti, S.; Piccirilli, M.C.;

 Circuits and Systems II: Analog and Digital Signal Processing, IEEE Transactions on , Volume: 47 , Issue: 1 , Jan. 1999
 [see also Circuits and Systems II: Express Briefs, IEEE Transactions on] , Volume: 47 , Issue: 1 , Jan. 1999

46 , Issue: 4 , April 1999
Pages:483 - 485

[[Abstract](#)] [[PDF Full-Text \(64 KB\)](#)] IEEE JNL

5 Sensitivity to errors in artificial neural networks: a behavioral approach

Alippi, C.; Piuri, V.; Sami, M.;

Circuits and Systems I: Fundamental Theory and Applications, IEEE Transactions on [see also Circuits and Systems I: Regular Papers, IEEE Transactions on] , Volume: 42 , Issue: 6 , June 1995

Pages:358 - 361

[[Abstract](#)] [[PDF Full-Text \(380 KB\)](#)] IEEE JNL

6 GLOBECOM '90: IEEE Global Telecommunications Conference and Exhibition. 'Communications: Connecting the Future' (Cat. No.90CH2814)

Global Telecommunications Conference, 1990, and Exhibition. 'Communication Connecting the Future', GLOBECOM '90., IEEE , 2-5 Dec. 1990

[[Abstract](#)] [[PDF Full-Text \(1292 KB\)](#)] IEEE CNF

7 Effects of radiation on digital architectures: one year results from a satellite experiment

Velazco, R.; Cheynet, P.; Ecoffet, R.;

Integrated Circuits and Systems Design, 1999. Proceedings. XII Symposium on , 29 Sept.-2 Oct. 1999

Pages:164 - 169

[[Abstract](#)] [[PDF Full-Text \(80 KB\)](#)] IEEE CNF

8 Fault-tolerant training of neural networks in the presence of MOS transistor mismatches

Orgenci, A.S.; Dundar, G.; Balkur, S.;

Circuits and Systems II: Analog and Digital Signal Processing, IEEE Transactions on [see also Circuits and Systems II: Express Briefs, IEEE Transactions on] , Volume: 48 , Issue: 3 , March 2001

Pages:272 - 281

[[Abstract](#)] [[PDF Full-Text \(212 KB\)](#)] IEEE JNL

9 Fault tolerance via weight noise in analog VLSI implementations of MLPs-a case study with EPSILON

Edwards, P.J.; Murray, A.F.;

Circuits and Systems II: Analog and Digital Signal Processing, IEEE Transactions on [see also Circuits and Systems II: Express Briefs, IEEE Transactions on] , Volume: 45 , Issue: 9 , Sept. 1998

Pages:1255 - 1262

[[Abstract](#)] [[PDF Full-Text \(132 KB\)](#)] IEEE JNL

10 Linear circuit fault diagnosis using neuromorphic analyzers

Spina, R.; Upadhyaya, S.;

Circuits and Systems II: Analog and Digital Signal Processing, IEEE Transacti
[see also Circuits and Systems II: Express Briefs, IEEE Transactions on] , Vol
44 , Issue: 3 , March 1997
Pages:188 - 196

[\[Abstract\]](#) [\[PDF Full-Text \(184 KB\)\]](#) IEEE JNL

11 A self-learning digital neural network using wafer-scale LSI

*Yasunaga, M.; Masuda, N.; Yagyu, M.; Asai, M.; Shibata, K.; Ooyama, M.; Yai
M.; Sakaguchi, T.; Hashimoto, M.;*

Solid-State Circuits, IEEE Journal of , Volume: 28 , Issue: 2 , Feb. 1993

Pages:106 - 114

[\[Abstract\]](#) [\[PDF Full-Text \(968 KB\)\]](#) IEEE JNL

12 Fault diagnosis of analog circuits using artificial neural networks as signature analyzers

Spina, R.; Upadhyaya, S.;

ASIC Conference and Exhibit, 1992., Proceedings of Fifth Annual IEEE
International , 21-25 Sept. 1992

Pages:355 - 358

[\[Abstract\]](#) [\[PDF Full-Text \(228 KB\)\]](#) IEEE CNF

13 Artificial neural networks in flight control and flight management systems

Burgin, G.H.; Schnetzler, S.S.;

Aerospace and Electronics Conference, 1990. NAECON 1990., Proceedings of t
IEEE 1990 National , 21-25 May 1990

Pages:567 - 573 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(516 KB\)\]](#) IEEE CNF

14 Towards the online diagnosis of faults in mixed signal circuits: a de sigma converter

Holding, J.M.; Jervis, B.W.;

Intelligent Sensor Processing (Ref. No. 2001/050), A DERA/IEE Workshop on ,
Feb. 2001

Pages:18/1 - 18/6

[\[Abstract\]](#) [\[PDF Full-Text \(428 KB\)\]](#) IEE CNF

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